# **N-Channel Power MOSFET** 600 V, 2.0 $\Omega$

#### **Features**

- Low ON Resistance
- Low Gate Charge
- ESD Diode-Protected Gate
- 100% Avalanche Tested
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

## **ABSOLUTE MAXIMUM RATINGS** ( $T_C = 25^{\circ}C$ unless otherwise noted)

Parameter	Symbol	NDF	NDD	Unit
Drain-to-Source Voltage	V <sub>DSS</sub>	600		٧
Continuous Drain Current $R_{\theta JC}$ (Note 1)	I <sub>D</sub>	4.8	4.1	Α
Continuous Drain Current $R_{\theta JC}$ , $T_A = 100^{\circ}C$ (Note 1)	I <sub>D</sub>	3.0	2.6	Α
Pulsed Drain Current, V <sub>GS</sub> @ 10V	I <sub>DM</sub>	20	20	Α
Power Dissipation $R_{\theta JC}$	$P_{D}$	30	83	W
Gate-to-Source Voltage	V <sub>GS</sub>	±3	30	٧
Single Pulse Avalanche Energy, I <sub>D</sub> = 4.0 A	E <sub>AS</sub>	120		mJ
ESD (HBM) (JESD22-A114)	V <sub>esd</sub>	3000		V
RMS Isolation Voltage (t = 0.3 sec., R.H. $\leq$ 30%, T <sub>A</sub> = 25°C) (Figure 15)	V <sub>ISO</sub>	4500	-	V
Peak Diode Recovery (Note 2)	dV/dt	4.5		V/ns
MOSFET dV/dt	dV/dt	60		V/ns
Continuous Source Current (Body Diode)	I <sub>S</sub>	4.0		Α
Maximum Temperature for Soldering Leads	TL	T <sub>L</sub> 260		°C
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	-55 to 150		°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

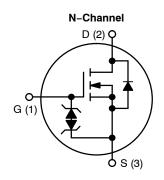
- 1. Limited by maximum junction temperature
- 2.  $I_{SD} = 4.0 \text{ A}, \text{ di/dt} \le 100 \text{ A/}\mu\text{s}, V_{DD} \le BV_{DSS}, T_J = +150^{\circ}\text{C}$



## ON Semiconductor®

### www.onsemi.com

V <sub>DSS</sub> (@ T <sub>Jmax</sub> )	R <sub>DS(on)</sub> (MAX) @ 2 A		
650 V	2.0 Ω		





NDF04N60ZG, NDF04N60ZH TO-220FP CASE 221AH



NDD04N60Z-1G **IPAK** CASE 369D



NDD04N60ZT4G DPAK CASE 369AA

## ORDERING AND MARKING INFORMATION

See detailed ordering, marking and shipping information on page 6 of this data sheet.

### THERMAL RESISTANCE

Parameter			Value	Unit
Junction-to-Case (Drain)	NDF04N60Z NDD04N60Z	$R_{ heta JC}$	4.2 1.5	°C/W
Junction-to-Ambient Steady State	(Note 3) NDF04N60Z (Note 4) NDD04N60Z (Note 3) NDD04N60Z-1	$R_{ hetaJA}$	50 38 80	

<sup>3.</sup> Insertion mounted

## **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise noted)

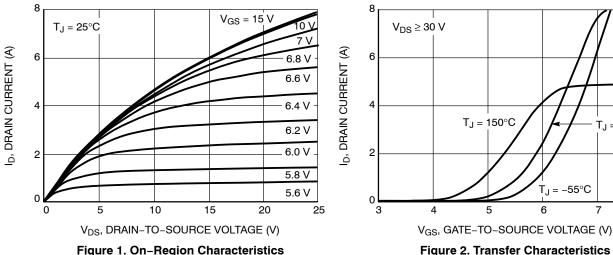
Characteristic	Test Conditions		Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$		BV <sub>DSS</sub>	600			V
Breakdown Voltage Temperature Co- efficient	Reference to 25°C, I <sub>D</sub> = 1 mA		$\Delta BV_{DSS}/ \Delta T_{J}$		0.6		V/°C
Drain-to-Source Leakage Current	V <sub>DS</sub> = 600 V, V <sub>GS</sub> = 0 V	25°C 150°C	I <sub>DSS</sub>			1 50	μΑ
Gate-to-Source Forward Leakage	V <sub>GS</sub> = ±20 V		I <sub>GSS</sub>			±10	μΑ
ON CHARACTERISTICS (Note 5)							
Static Drain-to-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 2.0 \text{ A}$	١	R <sub>DS(on)</sub>		1.8	2.0	Ω
Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 50 \mu A$	١	V <sub>GS(th)</sub>	3.0	3.9	4.5	V
Forward Transconductance	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 2.0 A	l	9FS		3.3		S
YNAMIC CHARACTERISTICS					•	•	•
Input Capacitance (Note 6)	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1.0 MHz		C <sub>iss</sub>	427	535	640	pF
Output Capacitance (Note 6)			C <sub>oss</sub>	50	62	75	
Reverse Transfer Capacitance (Note 6)			C <sub>rss</sub>	8	14	20	
Total Gate Charge (Note 6)	V <sub>DD</sub> = 300 V, I <sub>D</sub> = 4.0 A,		Qg	10	19	29	nC
Gate-to-Source Charge (Note 6)			Q <sub>gs</sub>	2	3.9	6	
Gate-to-Drain ("Miller") Charge	$V_{GS} = 10 \text{ V}$		$Q_{gd}$	5	10	15	nC
Plateau Voltage			V <sub>GP</sub>		6.5		V
Gate Resistance			$R_{g}$		4.7		Ω
RESISTIVE SWITCHING CHARACTERI	STICS						
Turn-On Delay Time			t <sub>d(on)</sub>		13		ns
Rise Time	$V_{DD} = 300 \text{ V}, I_D = 4.0 \text{ A}$	۸,	t <sub>r</sub>		9.0		
Turn-Off Delay Time	$V_{GS}$ = 10 V, $R_{G}$ = 5 $\Omega$		t <sub>d(off)</sub>		24		
Fall Time			t <sub>f</sub>		15		
OURCE-DRAIN DIODE CHARACTER	ISTICS (T <sub>C</sub> = 25°C unless other	erwise not	ed)				_
Diode Forward Voltage	I <sub>S</sub> = 4.0 A, V <sub>GS</sub> = 0 V		$V_{SD}$			1.6	V
Reverse Recovery Time	V <sub>GS</sub> = 0 V, V <sub>DD</sub> = 30 \	/	t <sub>rr</sub>		285		ns
Reverse Recovery Charge	$I_S = 4.0 \text{ A, di/dt} = 100 \text{ A/}\mu\text{s}$		Q <sub>rr</sub>		1.3		μС

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

<sup>4.</sup> Surface mounted on FR4 board using 1" sq. pad size (Cu area = 1.127 in sq [2 oz] including traces).

<sup>5.</sup> Pulse Width ≤ 380 μs, Duty Cycle ≤ 2%.
6. Guaranteed by design.

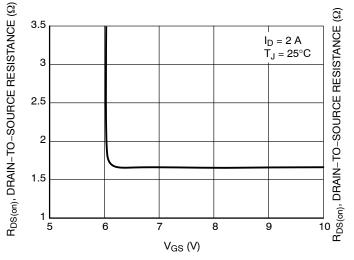
### **TYPICAL CHARACTERISTICS**



 $T_J = 150^{\circ}C$ T<sub>J</sub> = 25°C  $T_J = -55^{\circ}C$ 

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



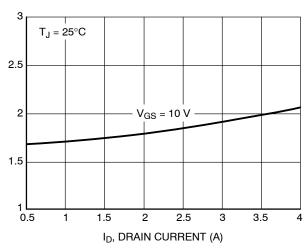
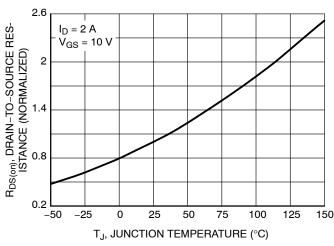


Figure 3. On-Resistance vs. Gate Voltage

Figure 4. On-Resistance vs. Drain Current and **Gate Voltage** 



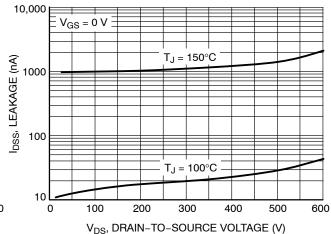
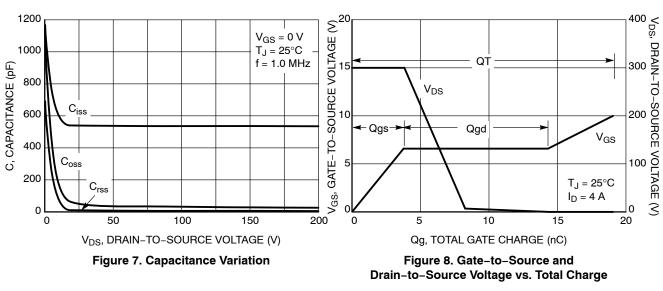


Figure 5. On-Resistance Variation with **Temperature** 

Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL CHARACTERISTICS**



SOURCE CURRENT (A)

<u>ŵ</u>

 $\begin{array}{c} 100 \\ \hline V_{DD} = 300 \text{ V} \\ \hline I_{D} = 4 \text{ A} \\ \hline V_{GS} = 10 \text{ V} \\ \hline \end{array}$ 

Figure 9. Resistive Switching Time Variation vs. Gate Resistance

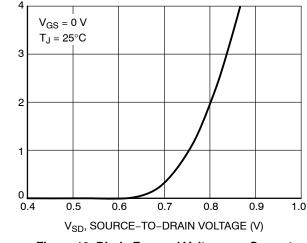


Figure 10. Diode Forward Voltage vs. Current

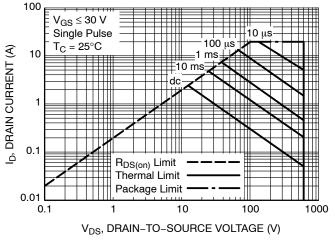


Figure 11. Maximum Rated Forward Biased Safe Operating Area for NDF04N60Z

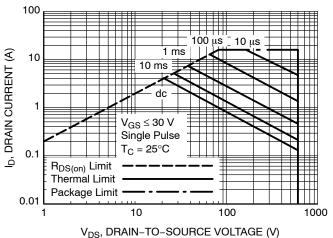


Figure 12. Maximum Rated Forward Biased Safe Operating Area for NDD04N60Z

#### **TYPICAL CHARACTERISTICS**

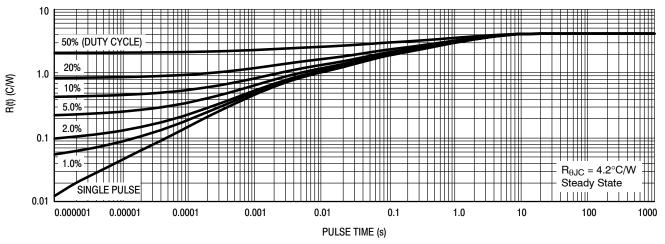


Figure 13. Thermal Impedance for NDF04N60Z

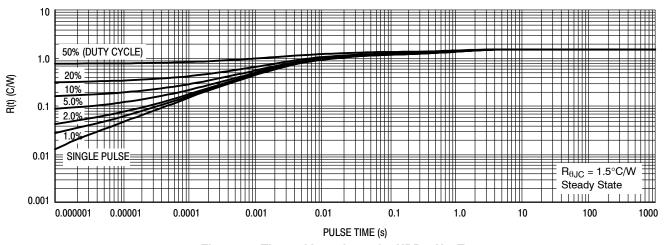


Figure 14. Thermal Impedance for NDD04N60Z

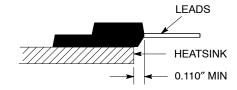


Figure 15. Mounting Position for Isolation Test

Measurement made between leads and heatsink with all leads shorted together.

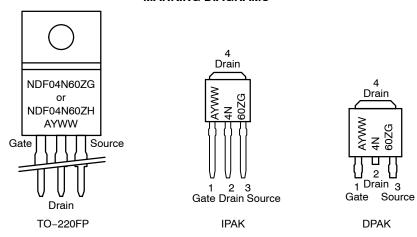
\*For additional mounting information, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

### **ORDERING INFORMATION**

Order Number	Package	Shipping <sup>†</sup>
NDF04N60ZG	TO-220FP (Pb-Free, Halogen-Free)	50 Units / Rail
NDF04N60ZH	TO-220FP (Pb-Free, Halogen-Free)	50 Units / Rail
NDD04N60Z-1G	IPAK (Pb-Free, Halogen-Free)	75 Units / Rail
NDD04N60ZT4G	DPAK (Pb-Free, Halogen-Free)	2500 / Tape and Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

## **MARKING DIAGRAMS**



A = Location Code\*

Y = Year

WW = Work Week

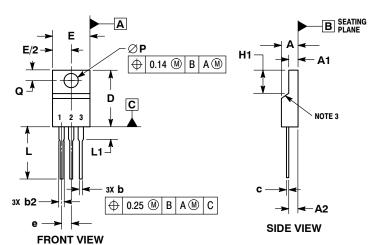
G, H = Pb-Free, Halogen-Free Package

<sup>\*</sup> The Assembly Location Code (A) is front side optional. In cases where the Assembly Location is stamped in the package bottom (molding ejecter pin), the front side assembly code may be blank.

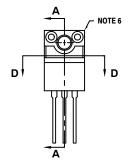
### **PACKAGE DIMENSIONS**

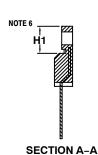
## TO-220 FULLPACK, 3-LEAD

CASE 221AH **ISSUE F** 









**ALTERNATE CONSTRUCTION** 

- NOTES:

  1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.

  2. CONTROLLING DIMENSION: MILLIMETERS.

  3. CONTOUR UNCONTROLLED IN THIS AREA.

  4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH AND GATE PROTRUSIONS. MOLD FLASH AND GATE PROTRUSIONS NOT TO EXCEED 0.13 PER SIDE. THESE DIMENSIONS ARE TO BE MEASURED AT OUTERMOST EXTREME OF THE PLASTIC BODY.

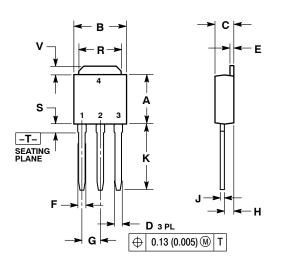
  5. DIMENSION DE DOES NOT INCLUDE DAMBAR PROTRUSION. LEAD WIDTH INCLUDING PROTRUSION SHALL NOT EXCEED 2.00.

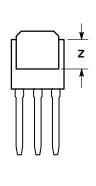
  6. CONTOURS AND FEATURES OF THE MOLDED PACKAGE BODY MAY VARY WITHIN THE ENVELOP DEFINED BY DIMENSIONS A1 AND H1 FOR MANUFACTURING PURPOSES.

	MILLIMETERS			
DIM	MIN	MAX		
Α	4.30	4.70		
A1	2.50	2.90		
A2	2.50	2.90		
b	0.54	0.84		
b2	1.10	1.40		
С	0.49	0.79		
D	14.70	15.30		
Ε	9.70	10.30		
е	2.54	BSC		
H1	6.60	7.10		
L	12.50	14.73		
L1		2.80		
P	3.00	3.40		
O	2 80	3 20		

## **PACKAGE DIMENSIONS**

# **IPAK** CASE 369D ISSUE C





- NOTES:
  1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
  2. CONTROLLING DIMENSION: INCH.

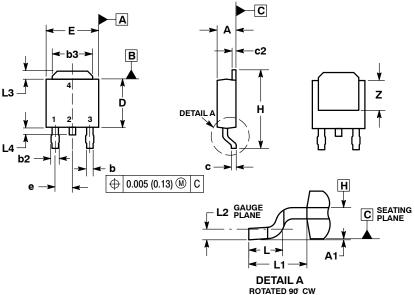
	INC	HES	MILLIMETERS		
DIM	MIN	MAX	MIN	MAX	
Α	0.235	0.245	5.97	6.35	
В	0.250	0.265	6.35	6.73	
С	0.086	0.094	2.19	2.38	
D	0.027	0.035	0.69	0.88	
Е	0.018	0.023	0.46	0.58	
F	0.037	0.045	0.94	1.14	
G	0.090 BSC		2.29 BSC		
Н	0.034	0.040	0.87	1.01	
J	0.018	0.023	0.46	0.58	
K	0.350	0.380	8.89	9.65	
R	0.180	0.215	4.45	5.45	
S	0.025	0.040	0.63	1.01	
٧	0.035	0.050	0.89	1.27	
Z	0.155		3.93		

STYLE 2: PIN 1. GATE 2. DRAIN 3. SOURCE 4. DRAIN

### PACKAGE DIMENSIONS

## **DPAK (SINGLE GAUGE)**

CASE 369AA **ISSUE B** 



#### NOTES

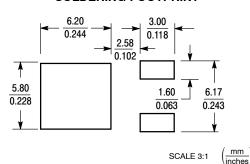
- 1. DIMENSIONING AND TOLERANCING PER ASME
- Y14.5M, 1994.
  2. CONTROLLING DIMENSION: INCHES.
- THERMAL PAD CONTOUR OPTIONAL WITHIN DI-MENSIONS b3, L3 and Z.
- DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL
- NOT EXCEED 0.006 INCHES PER SIDE.
  DIMENSIONS D AND E ARE DETERMINED AT THE
  OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 6. DATUMS A AND B ARE DETERMINED AT DATUM PI ANF H

	INC	HES	MILLIMETERS		
DIM	MIN	MAX	MIN	MAX	
Α	0.086	0.094	2.18	2.38	
A1	0.000	0.005	0.00	0.13	
b	0.025	0.035	0.63	0.89	
b2	0.030	0.045	0.76	1.14	
b3	0.180	0.215	4.57	5.46	
С	0.018	0.024	0.46	0.61	
c2	0.018	0.024	0.46	0.61	
D	0.235	0.245	5.97	6.22	
E	0.250	0.265	6.35	6.73	
е	0.090 BSC		2.29	BSC	
Н	0.370	0.410	9.40	10.41	
L	0.055	0.070	1.40	1.78	
L1	0.108 REF		2.74 REF		
L2	0.020	BSC	0.51 BSC		
L3	0.035	0.050	0.89	1.27	
L4		0.040		1.01	
Z	0.155		3.93		

## STYLE 2: PIN 1. GATE

- - 2. DRAIN 3. SOURCE
  - DRAIN

#### **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

ON Semiconductor and the are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at <a href="https://www.onsemi.com/site/pdf/Patent-Marking.pdf">www.onsemi.com/site/pdf/Patent-Marking.pdf</a>. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages.

Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold ON Semiconductor and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that ON Semiconductor was negligent regarding the design or manufacture of the part. ON Semiconductor is an Equal Opportunity/Affirmative Action Employer. This literature is subject to all applicable copyright laws and is not for resale in any manner.

## **PUBLICATION ORDERING INFORMATION**

## LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com

N. American Technical Support: 800-282-9855 Toll Free USA/Canada

Europe, Middle East and Africa Technical Support: Phone: 421 33 790 2910 Japan Customer Focus Center

ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative

Phone: 81-3-5817-1050